S arch Notes

Ap	plication/C ntr I No.	Applicant(s)/Patent under R examinati n	r
10/	/521,683	SCHMIDT ET AL.	
Exa	aminer	Art Unit	
 Ha	i H. Huynh	3747	

SEARCHED					
Class	Subclass	Date	Examiner		
123	598	5/23/2006	ннн		
123	599	5/23/2006	ннн		
123	601	5/23/2006	ннн		
123	605-606	5/23/2006	ннн		
123	608	5/23/2006	ннн		
123	143B	5/23/2006	ннн		
123	634	5/23/2006	ннн		
333	246-248	5/23/2006	ннн		
333	99PL	5/23/2006	ннн		

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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